



ALPHA & OMEGA
SEMICONDUCTOR

AOD450
200V N-Channel MOSFET

General Description

The AOD450 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in inverter, load switching and general purpose applications.

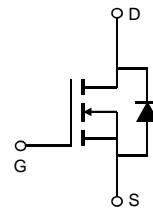
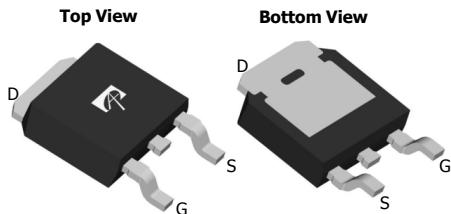
Product Summary

V_{DS}	200V
I_D (at $V_{GS}=10V$)	3.8A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 0.70Ω

100% UIS Tested
100% R_g Tested



**TO252
DPAK**



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	200	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current	I_D	3.8	A
$T_C=100^\circ C$		2.7	
Pulsed Drain Current ^C	I_{DM}	10	
Avalanche Current ^C	I_{AS}	3	A
Avalanche energy $L=1.35mH$ ^C	E_{AS}	6	mJ
Power Dissipation ^B	P_D	25	W
$T_C=100^\circ C$		12.5	
Power Dissipation ^A	P_{DSM}	2.1	W
$T_A=70^\circ C$		1.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	17.1	30	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		50	60	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	4	6	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=10\text{mA}, V_{GS}=0\text{V}$	200			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=160\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm30\text{V}$			±100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	3	5	6	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.8\text{A}$ $T_J=125^\circ\text{C}$		0.55 1.1	0.7 1.32	Ω
g_{FS}	Forward Transconductance	$V_{DS}=15\text{V}, I_D=3.8\text{A}$		8.7		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.8	1	V
I_S	Maximum Body-Diode Continuous Current ^G				6	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$	170	215	260	pF
C_{oss}	Output Capacitance		20	32	50	pF
C_{rss}	Reverse Transfer Capacitance		3	7.2	15	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		5.5		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=25\text{V}, I_D=3.8\text{A}$		3.82		nC
$Q_g(4.5\text{V})$	Total Gate Charge			0.92		nC
Q_{gs}	Gate Source Charge			1.42		nC
Q_{gd}	Gate Drain Charge			1.47		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=25\text{V}, R_L=6.5\Omega, R_{\text{GEN}}=3\Omega$		6.3		ns
t_r	Turn-On Rise Time			3.3		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			10.5		ns
t_f	Turn-Off Fall Time			2.8		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		59		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		142		nC

A. The value of R_{QJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{QJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.

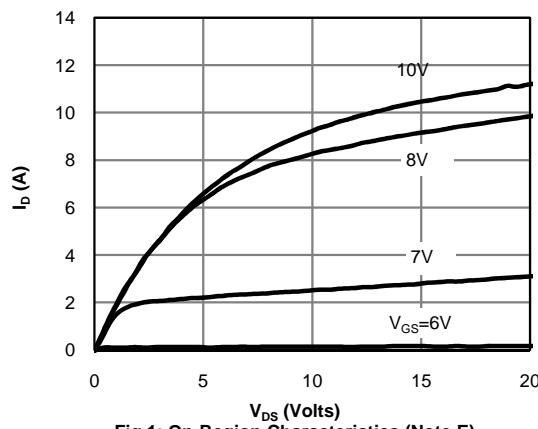
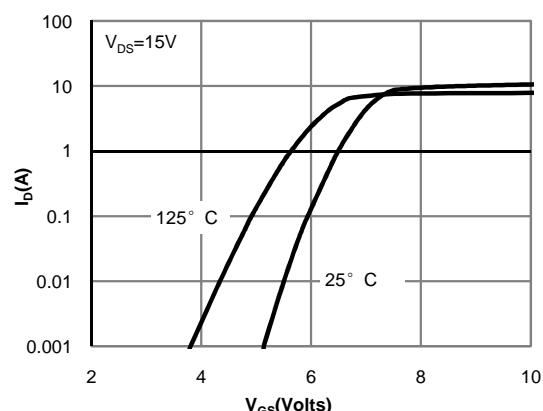
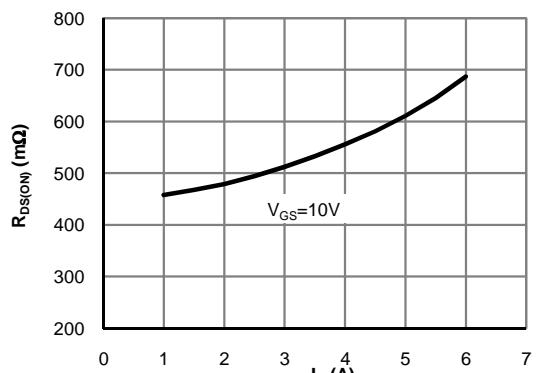
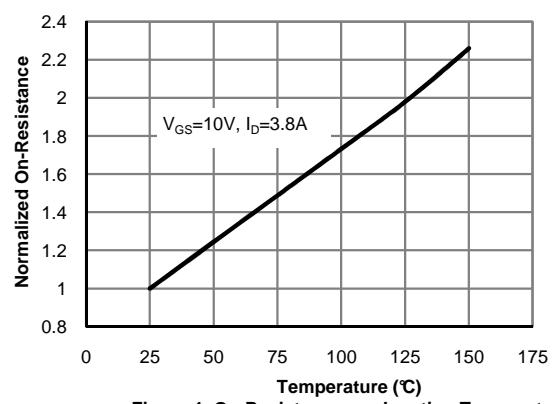
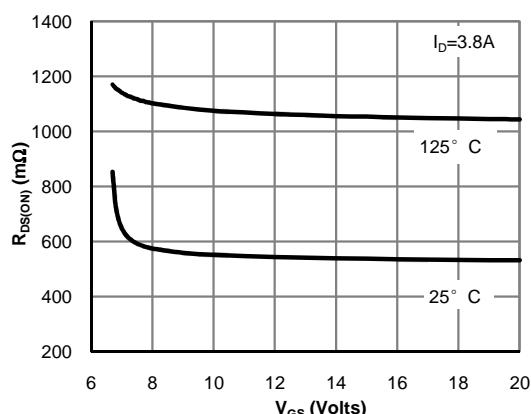
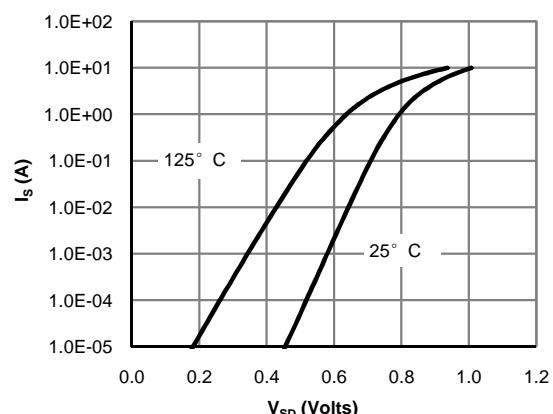
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

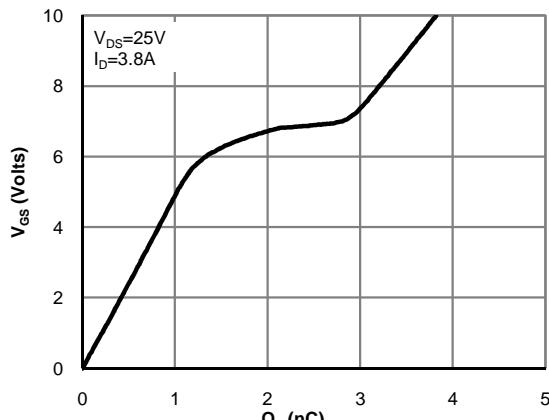
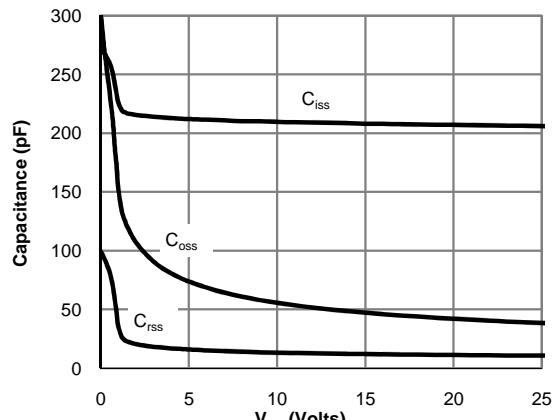
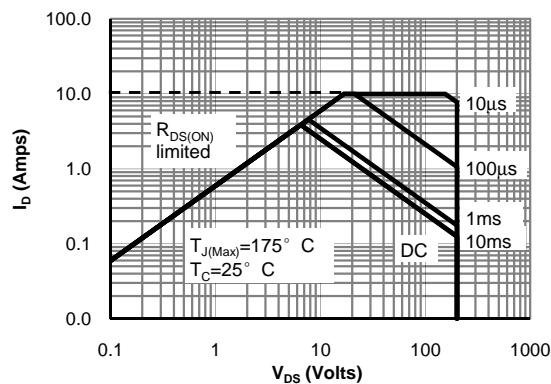
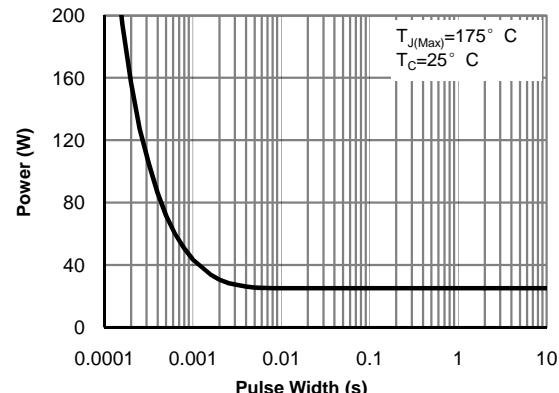
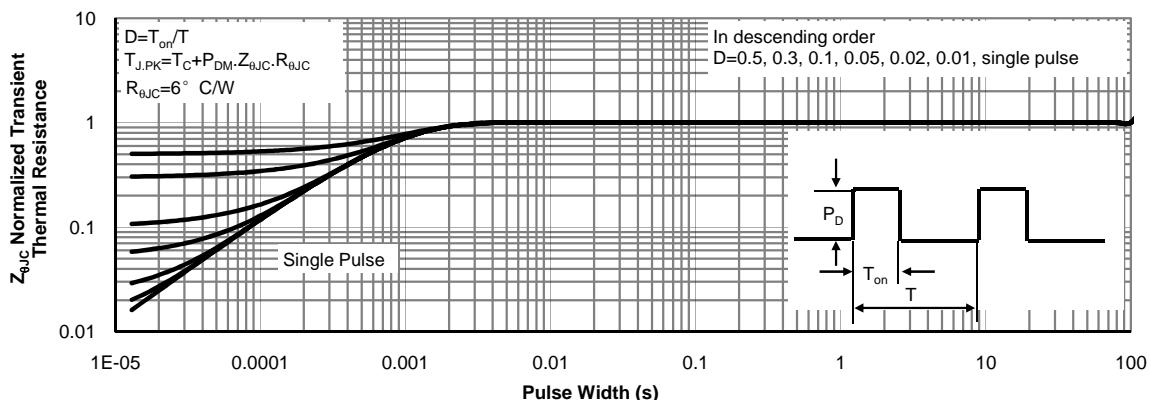
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

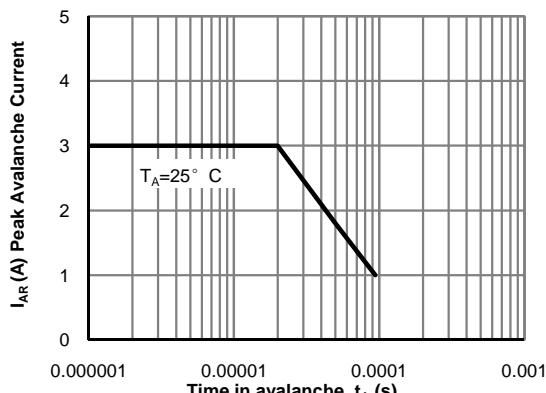
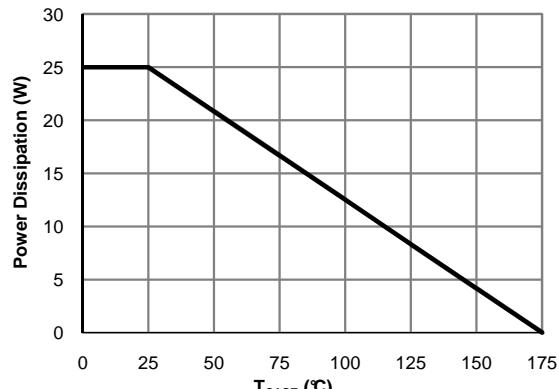
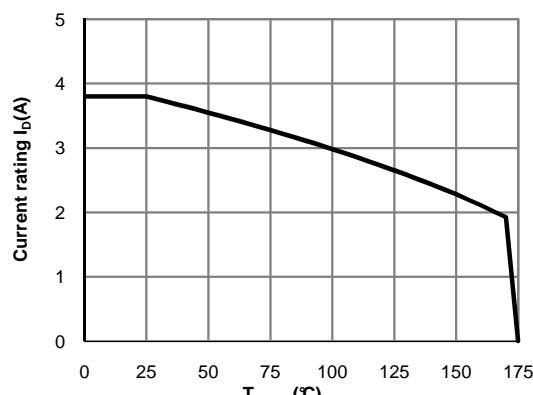
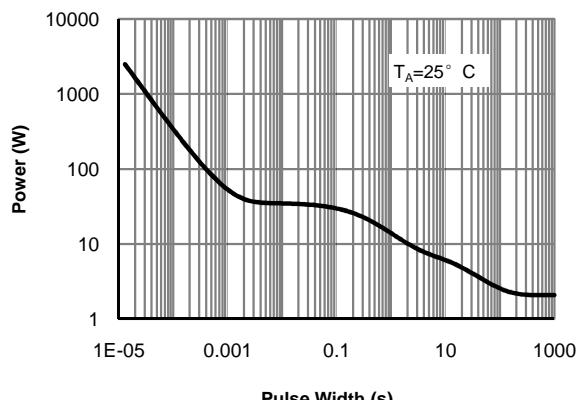
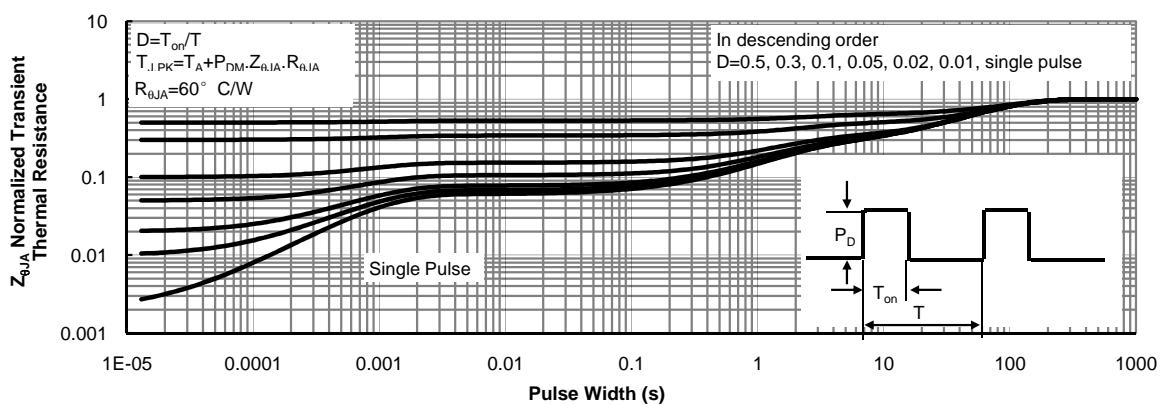
G. The maximum current rating is package limited.

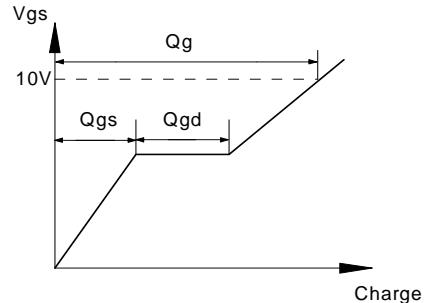
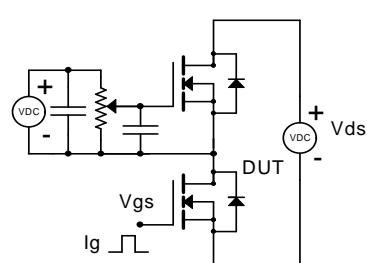
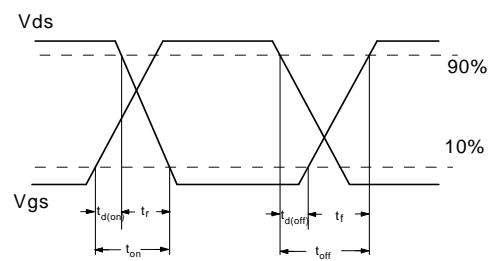
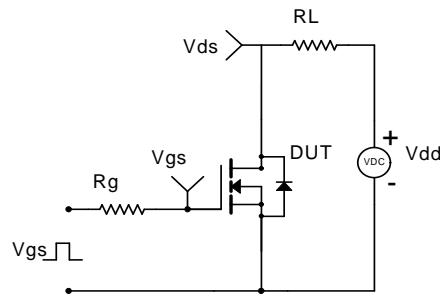
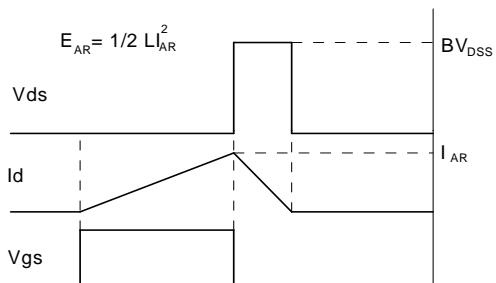
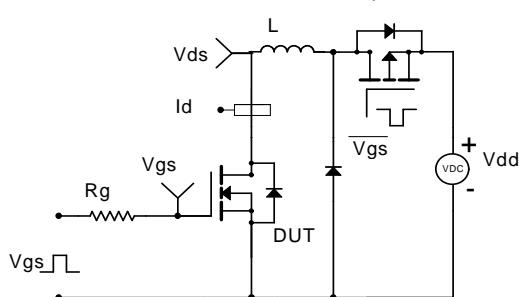
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Single Pulse Avalanche capability (Note C)

Figure 13: Power De-rating (Note F)

Figure 14: Current De-rating (Note F)

Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
